

Direct observation of effective atomic diffusion distances in Zr/2Al multilayers due to self-propagating reactions

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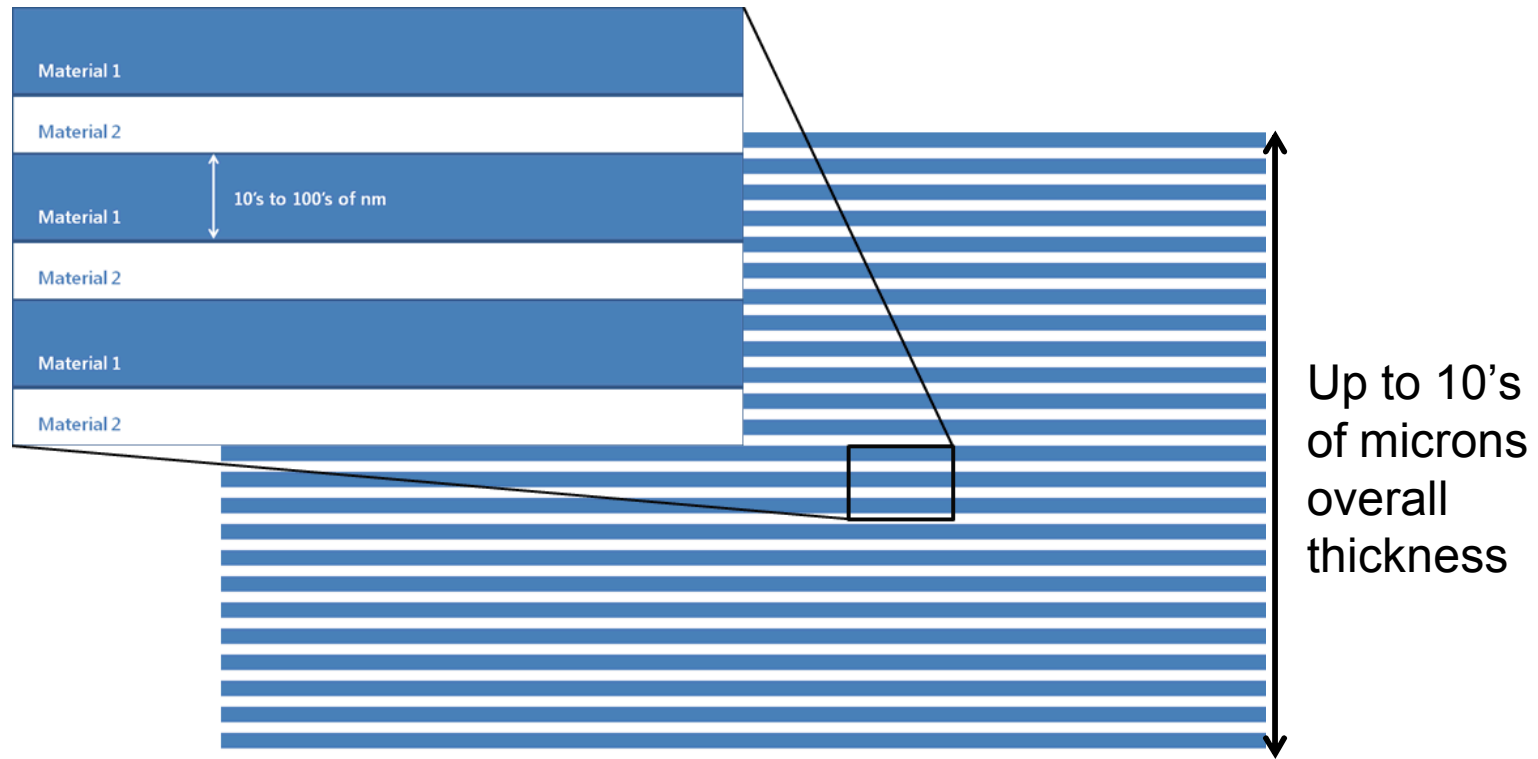


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Experimental Material

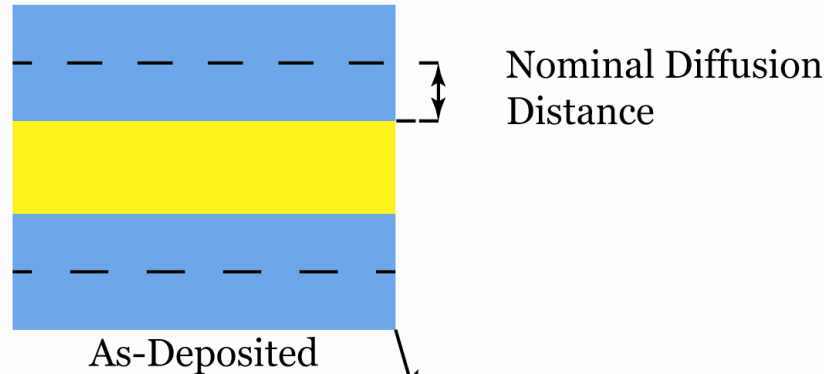
Zr/2Al Nanolaminates

- $Zr + 2Al \rightarrow ZrAl_2; \Delta H_{exp} = -46 \frac{kJ}{mol_{atoms}}$
(de Boer, Boom, Mattens, Miedema, Niessen, *Cohesion in Metals*, 1988)
- Typical design of sputtered reactive foils
 - Used extensively by Weihs, Adams, Rogachev, and others
 - Macroscale stacks of nanometric metal layers
 - Clean interfaces, high purity materials

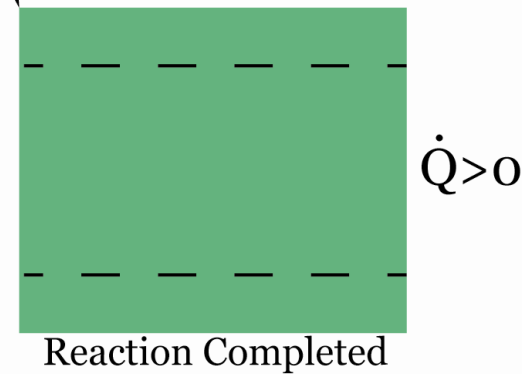
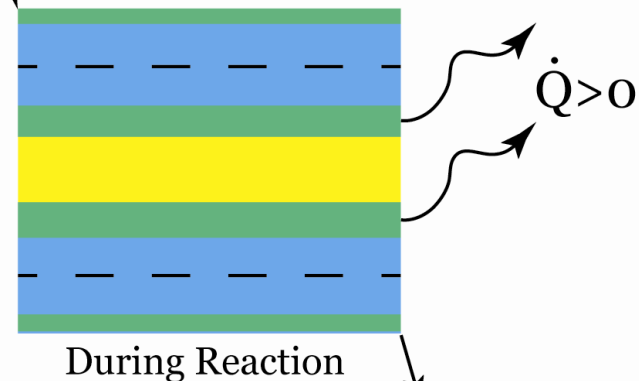


Nanolaminates

Typical Reaction Progression



- Atoms diffuse to center line of neighboring reactant layer
- Final phase formed once this distance is traveled
- Can other mechanisms affect diffusion distance?
 - Dissipative thermodynamics
 - High temperature diffusion

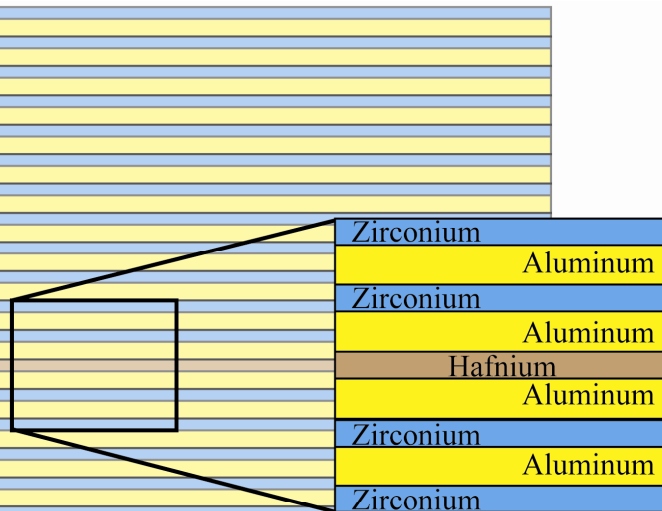


Marker Layer Design

Zr+(Hf)/2Al Nanolaminates

Compare ph
properties
DSC results

- Hafnium replaces Zr at a single layer
- Hafnium and Zr are miscible with no distinct intermetallic phases
- Similar chemistry and product phases with Al

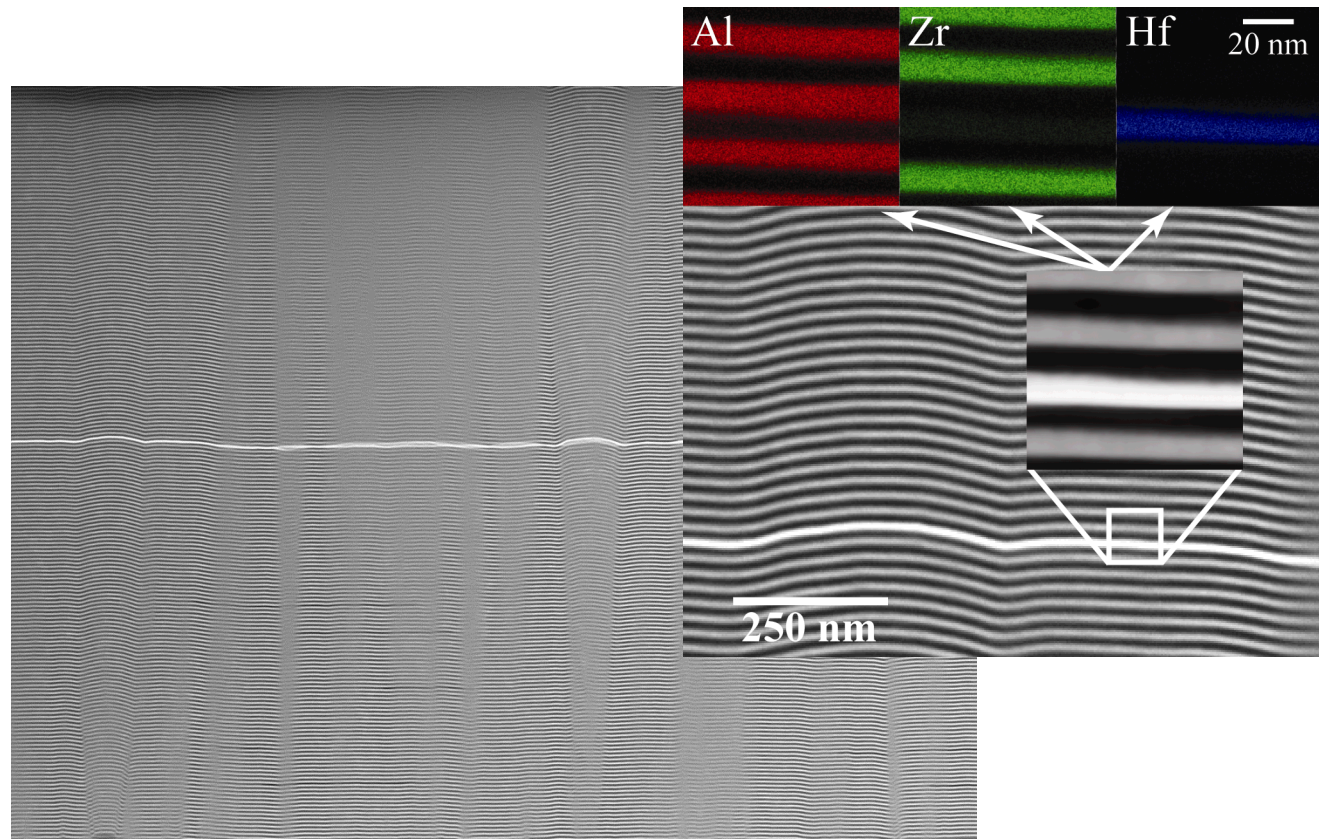


ZrAl ₂	T _m = 1660 °C	HfAl ₂	T _m = 1650 °C
	ΔH = -46 kJ/mol		ΔH = -48 kJ/mol
hP12	a = 0.52824	hP12	a = 0.525
	b = 0.52824		b = 0.525
	c = 0.87482		c = 0.868
Zr ₂ Al ₃	T _m ≈ 1590 °C	Hf ₂ Al ₃	T _m = 1660 °C
	ΔH = -47 kJ/mol		ΔH = -48 kJ/mol
oF40	a = 0.9601	oF40	a = 0.9529
	b = 1.3906		b = 1.3763
	c = 0.5574		c = 0.5525

Marker Layer Design

Zr+(Hf)/2Al Nanolaminates

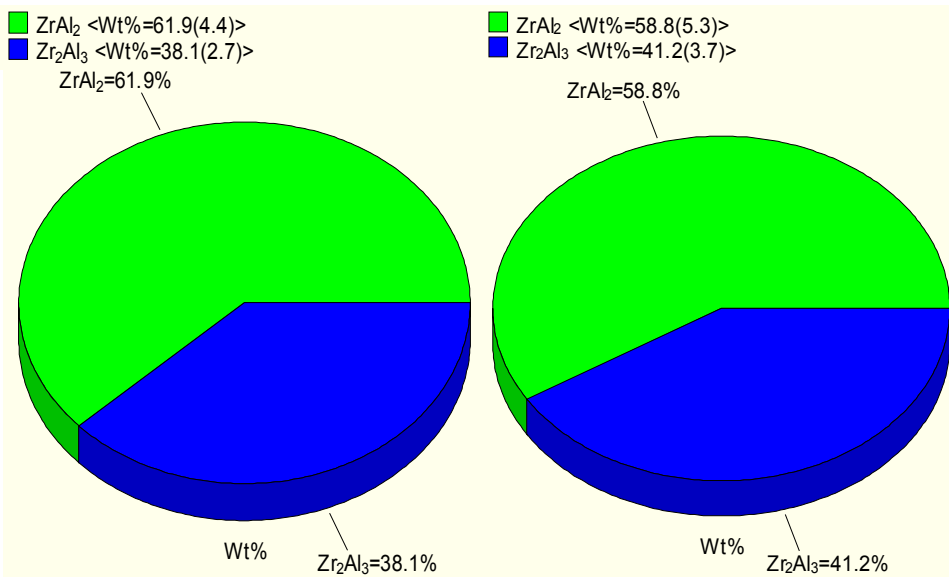
- Marker layer distinct
- Clearly resolvable with z-contrast and EDS in TEM



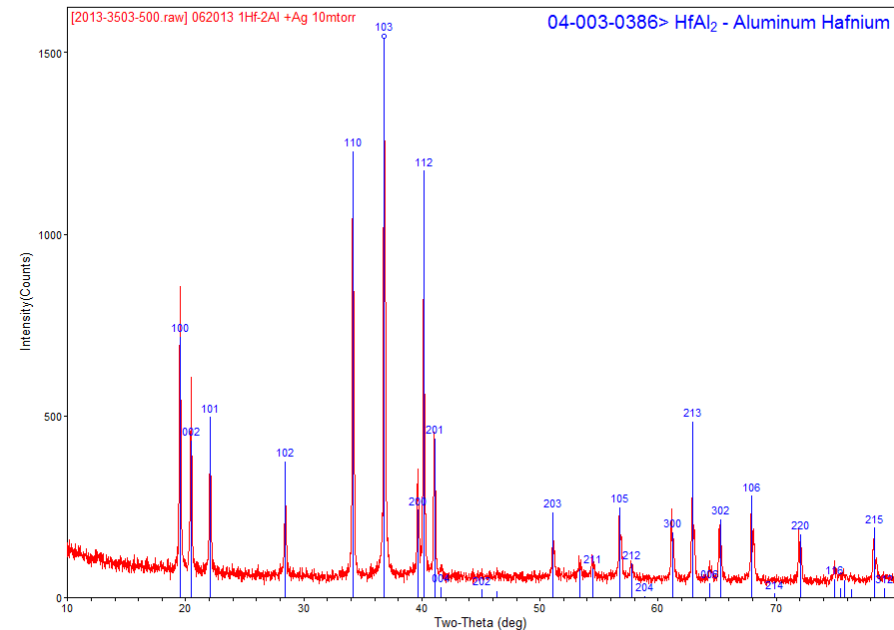
Phase Identification

Zr/2Al and Hf/2Al Standards

- Zr/2Al films reacted in vacuum (10 mTorr)
- ZrAl_2 (~60% wt%) and Zr_2Al_3 (~40% wt%) phases identified by XRD



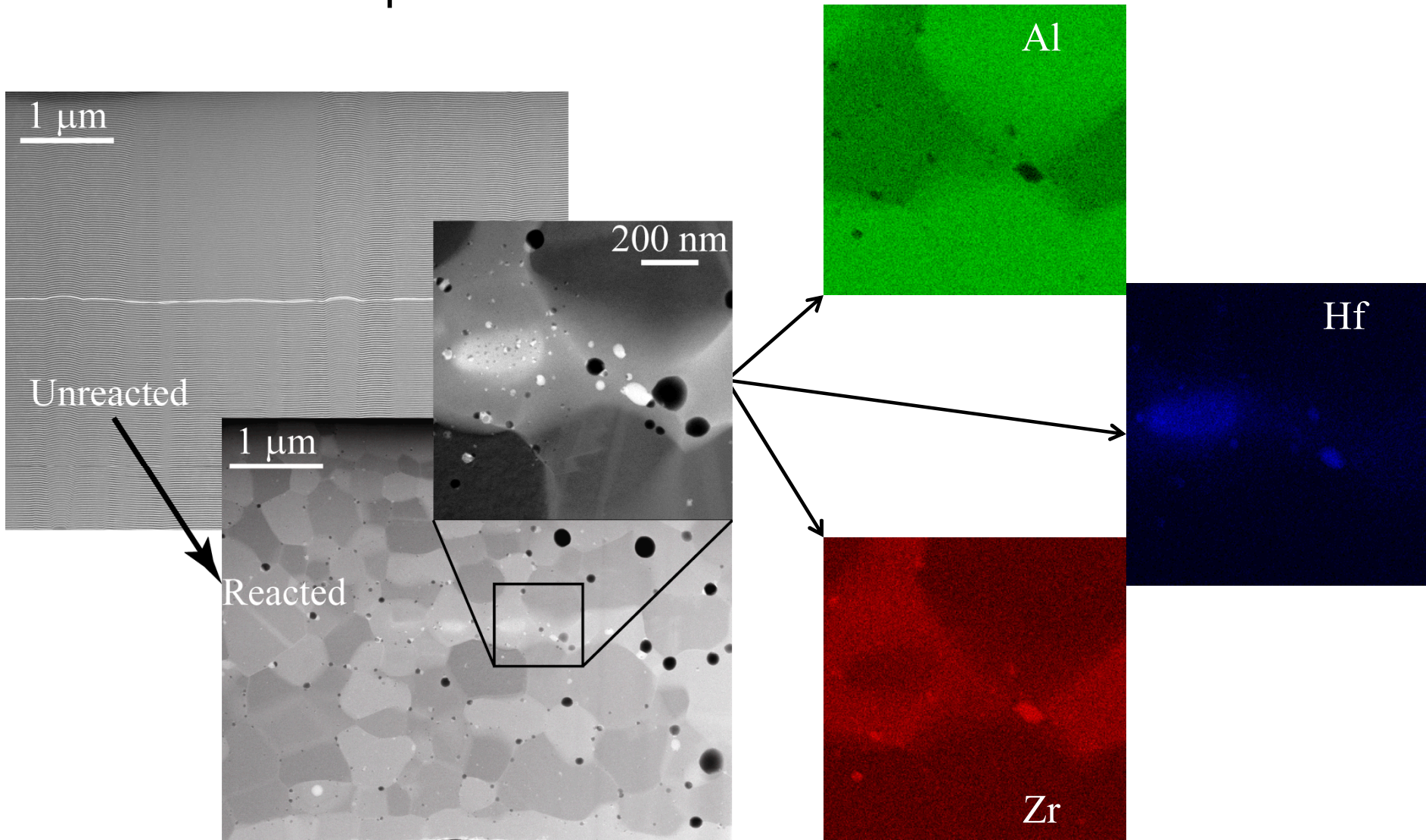
- Hf/2Al films reacted in vacuum (10 mTorr)
- Phase pure HfAl_2



Marker Layer Design

Zr+(Hf)/2Al Nanolaminates

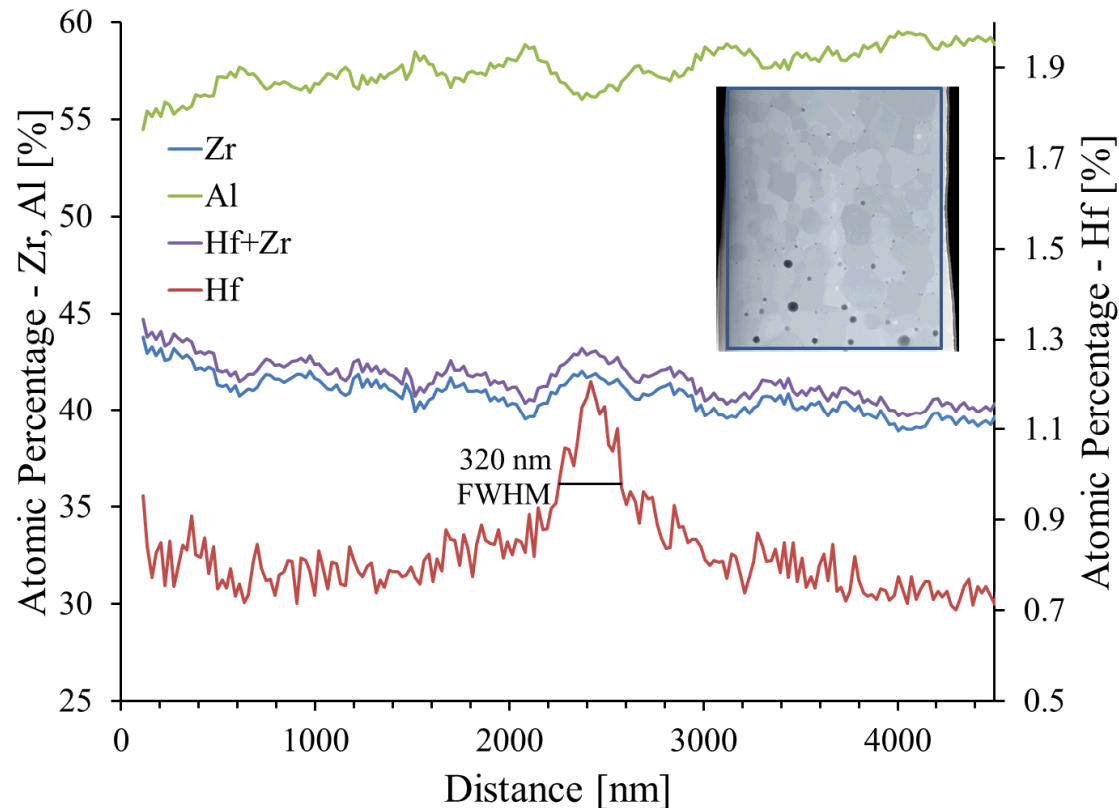
- Reaction disperses Hf marker material



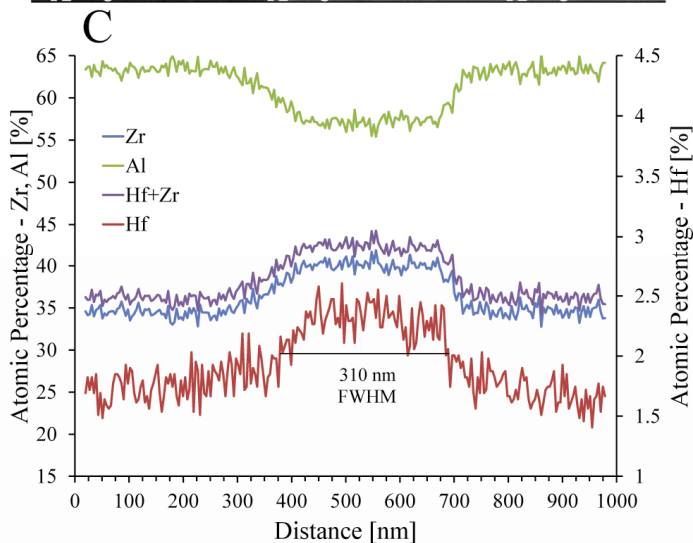
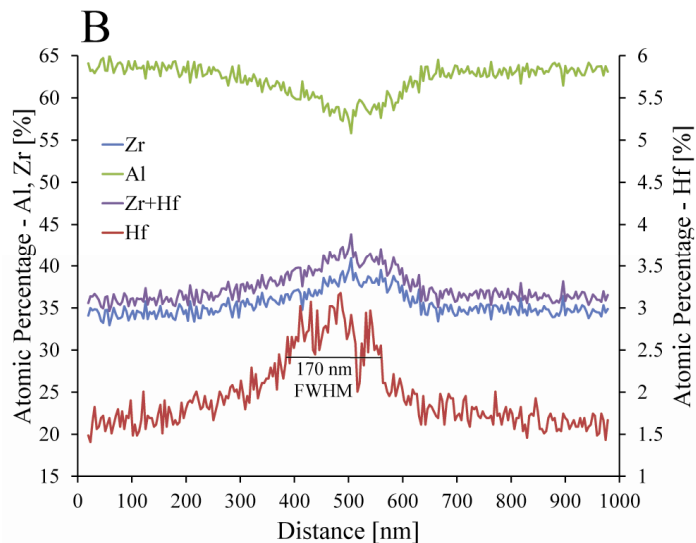
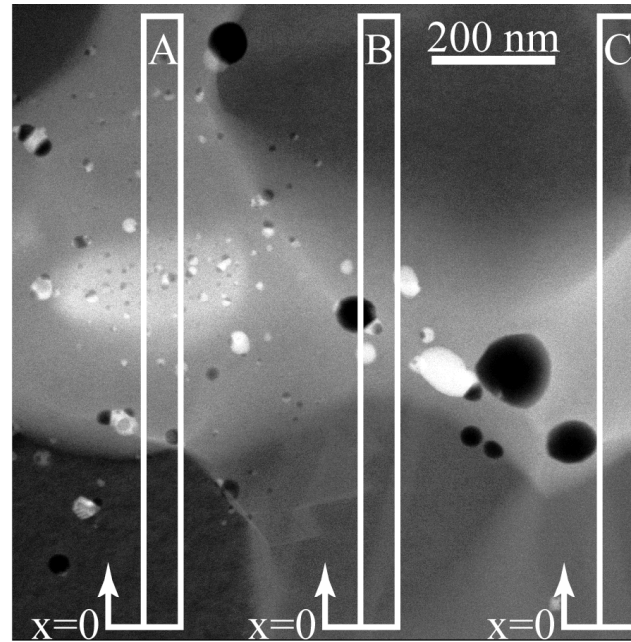
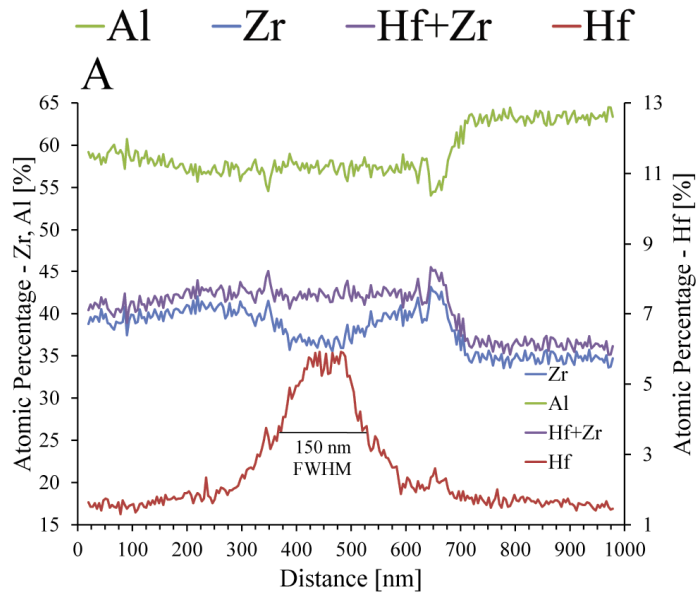
Marker Layer Design

Zr+(Hf)/2Al Nanolaminates

- Reaction disperses Hf marker material
- 14 kx magnification – 5 x 5 μm ROI
- Probed through EDS and SIMS



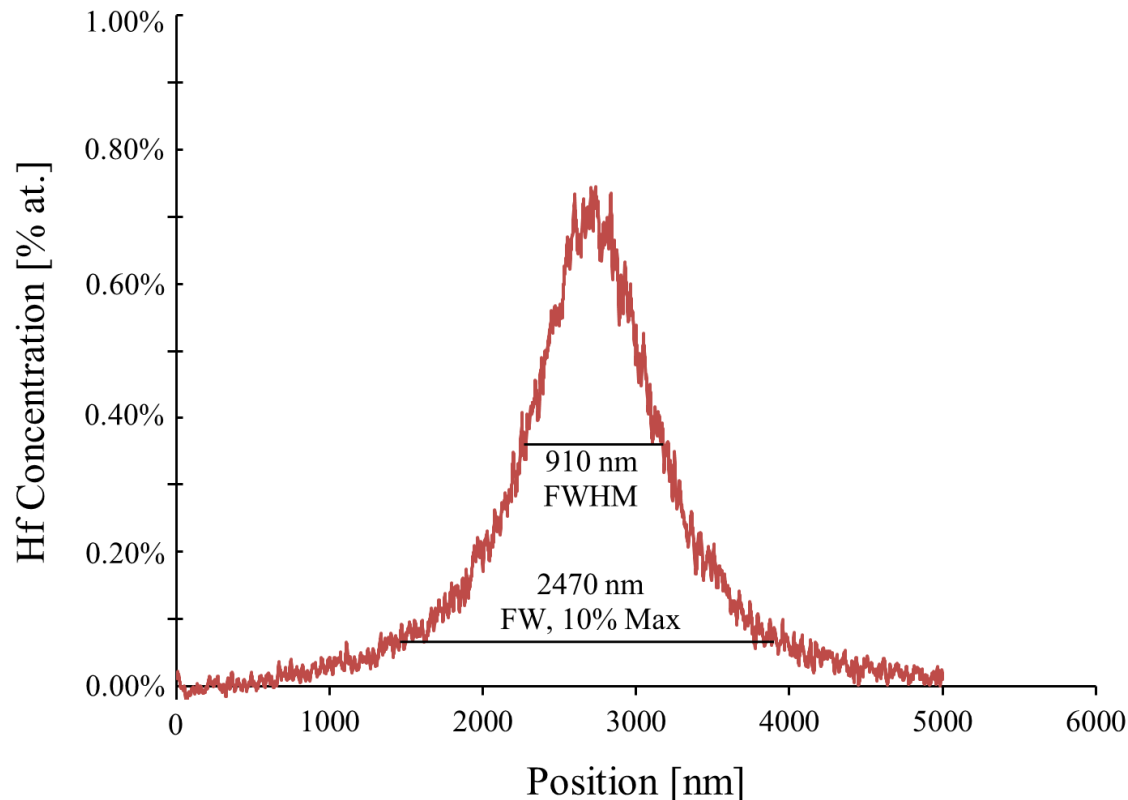
Variation at smaller length scales



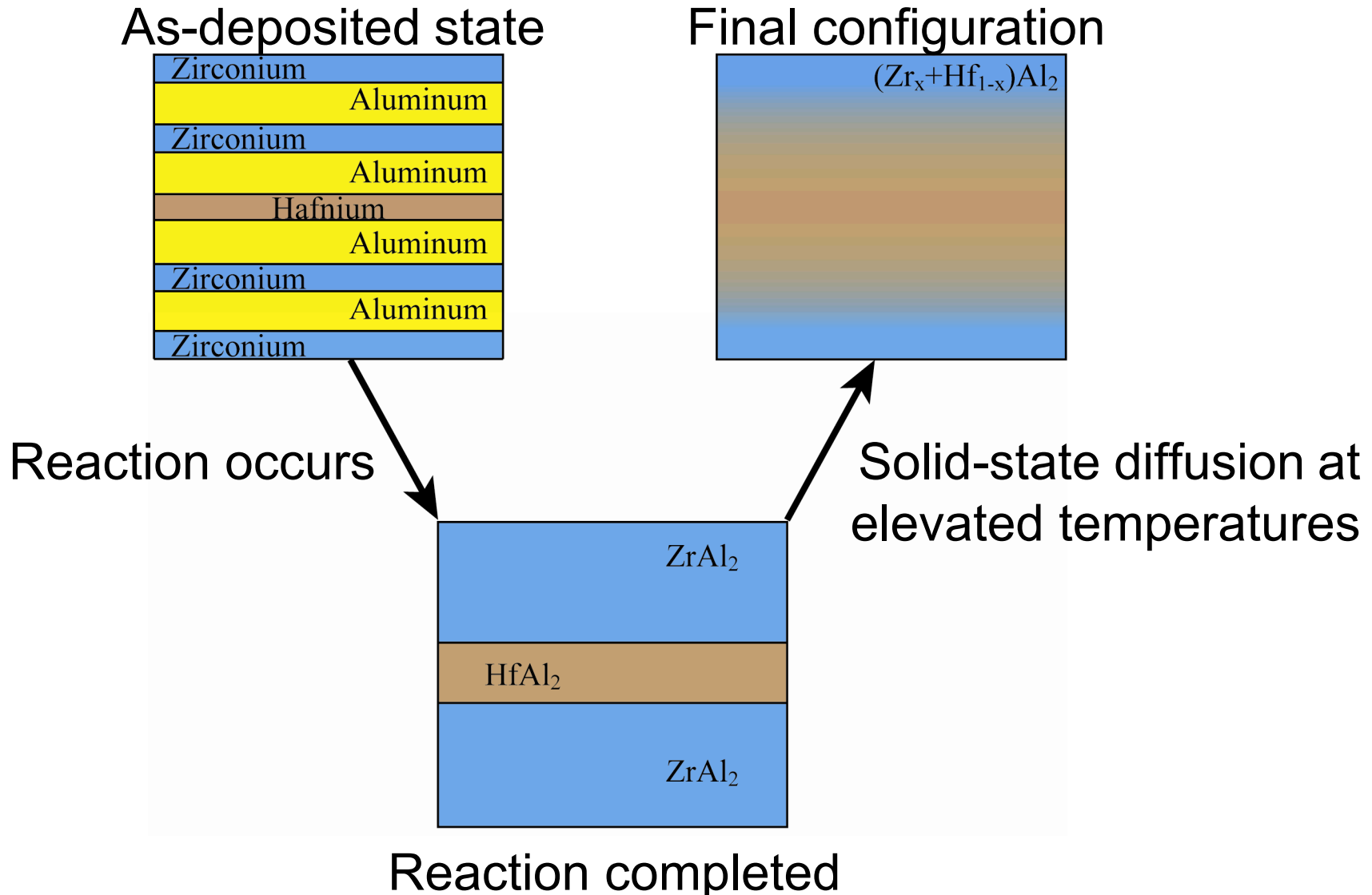
Marker Analysis by SIMS

Zr+(Hf)/2Al Nanolaminates

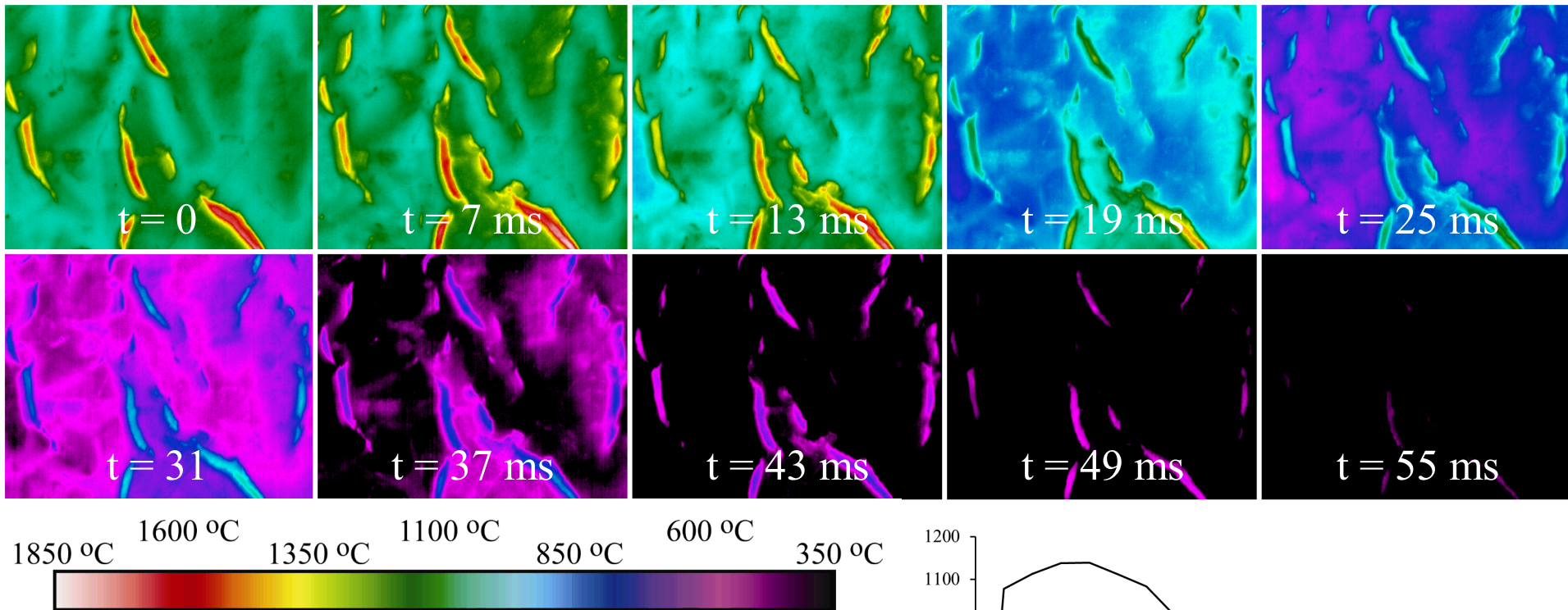
- Sputter area = $200 \times 200 \mu\text{m}^2$
- Analysis area = $50 \times 50 \mu\text{m}^2$ – much greater area than EDS
- Hf-baseline subtracted from signal



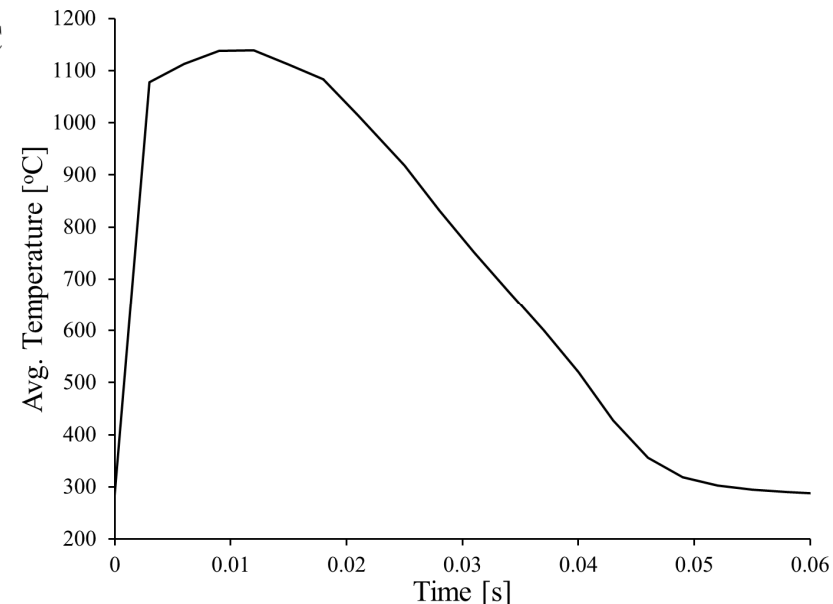
Diffusion model – Assumed progression



IR imaging of temperature history

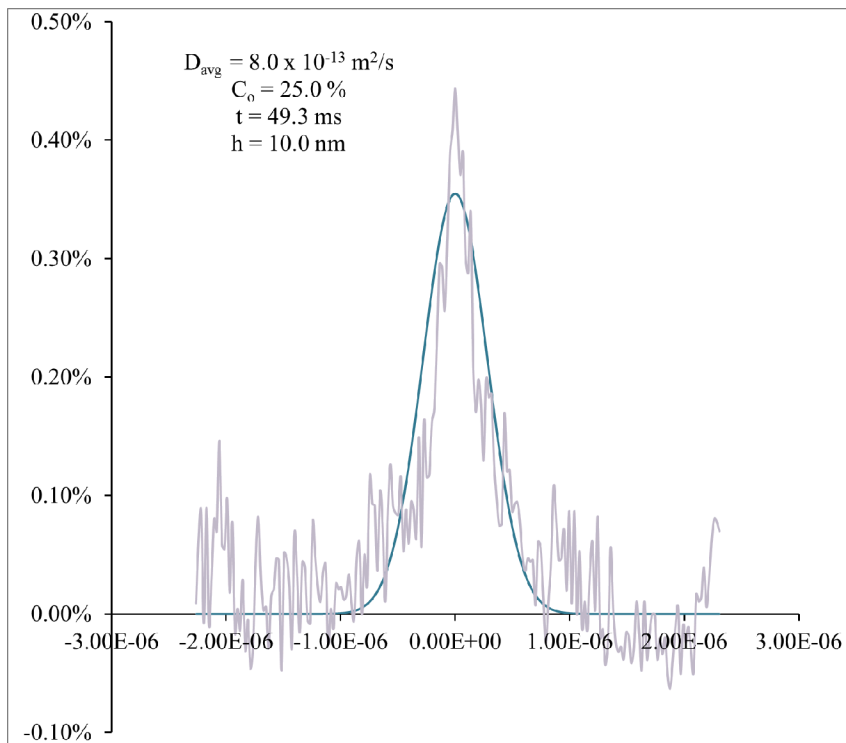


- Plot is average meas. temp of surface in image (4.8 x 3.8 mm)
- Time average over 46 ms is 690 °C (963 K)
- Information for comparison to best fit results from diffusion model



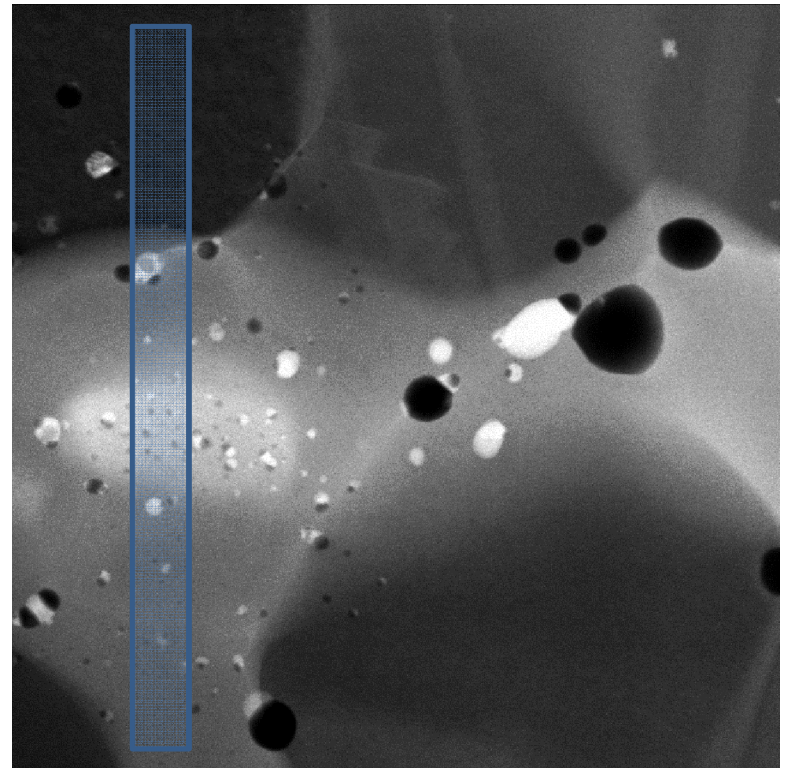
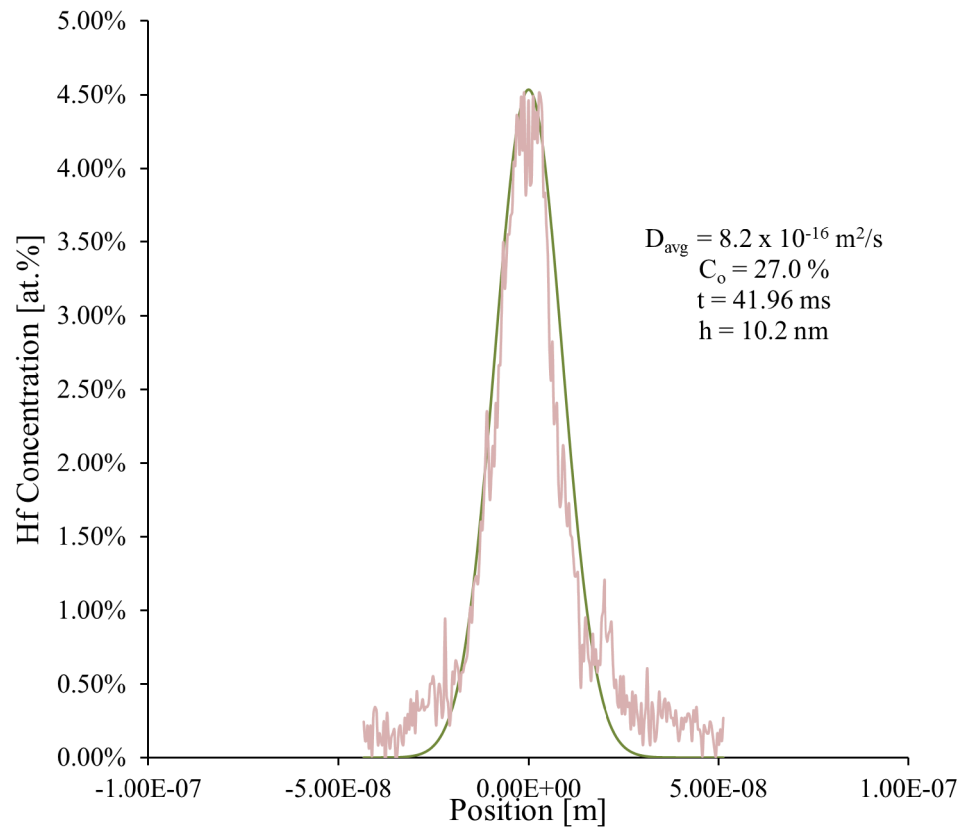
Diffusion model – Compare to EDS data

- Integration of EDS Hf signal over full 14 kx image (5x5 μm)
- Fits do not match well with simple diffusion model and assumptions



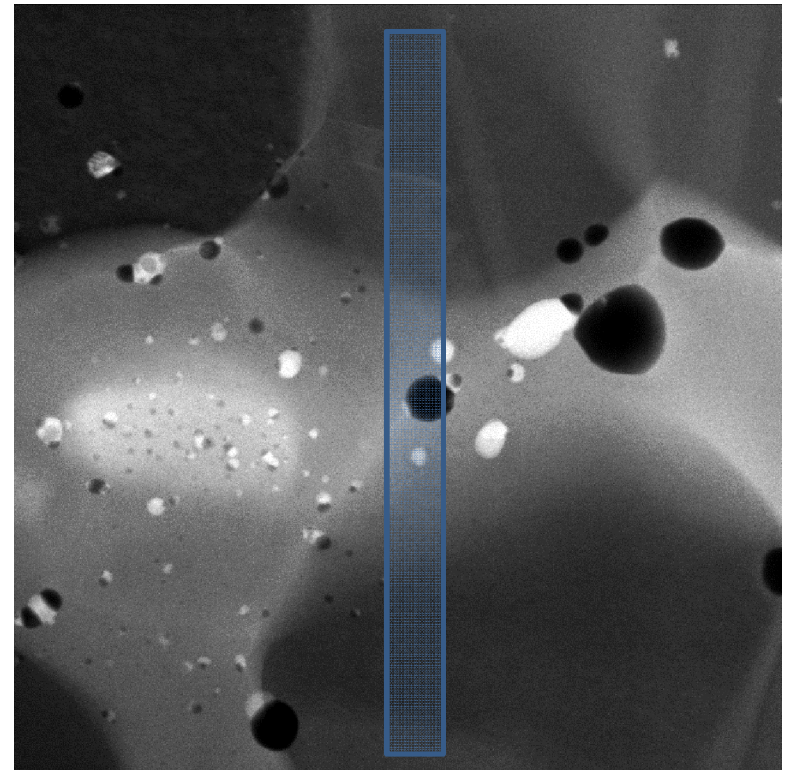
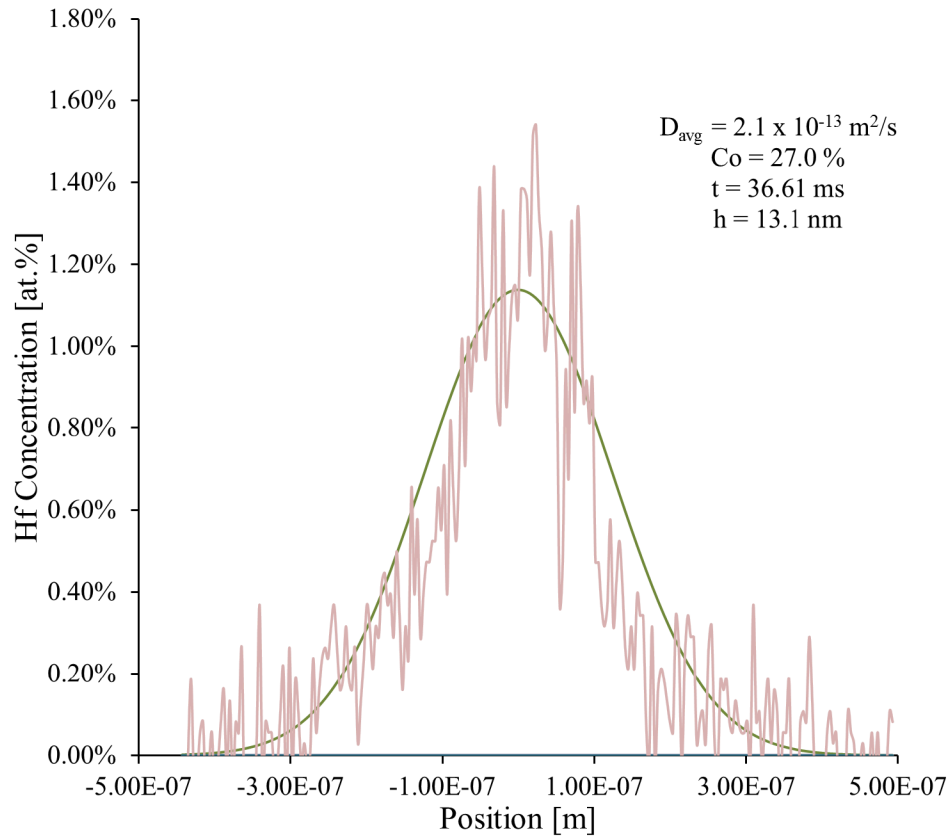
Diffusion model – Compare to EDS data

- Integrated profile across 40 nm x 1000 nm path (shown)
- Best fit $D = 8.2 \times 10^{-16} \text{ m}^2/\text{s}$



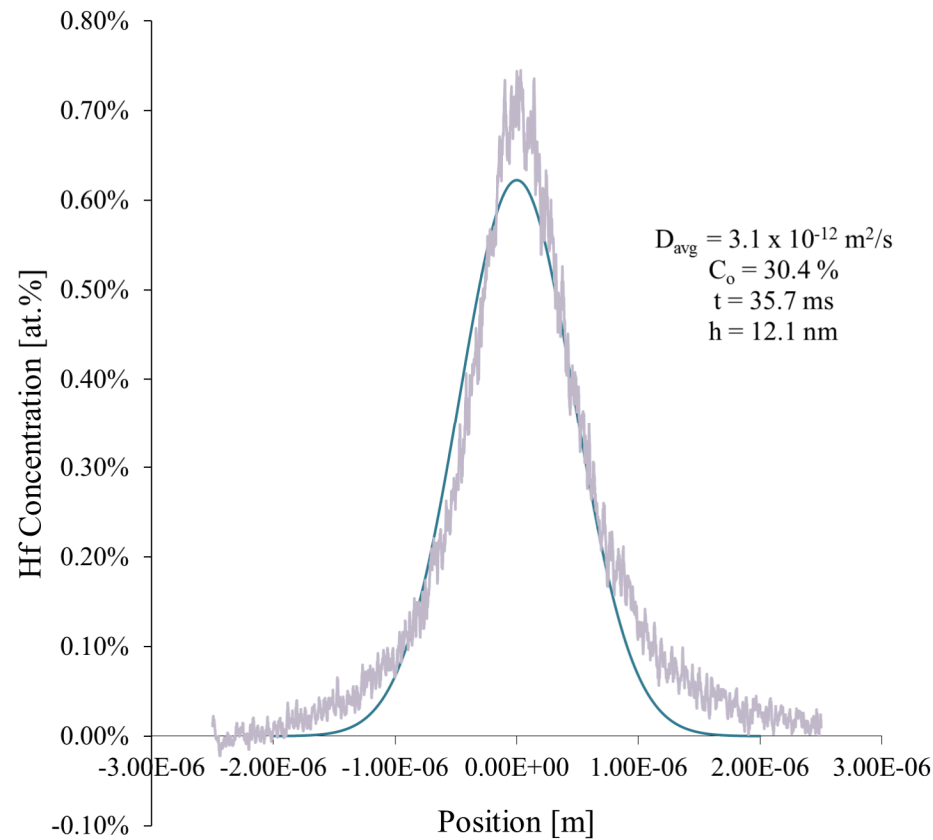
Diffusion model – Compare to EDS data

- Integrated profile across 40 nm x 1000 nm path (shown)
- Best fit $D = 2.1 \times 10^{-13} \text{ m}^2/\text{s}$



Diffusion model – Compare to SIMS data

- Best fit $D = 3.1 \times 10^{-12} \text{ m}^2/\text{s}$
Average D is consistent
with solid-state diffusion, at
960 K



Conclusions

- TEM-EDS and SIMS methodologies allow spatial tracking of marker layers in reactive multilayers
- Resolution
 - TEM-EDS: spatial: nm, concentration: 0.1%
 - SIMS: spatial?, concentration: ppm
- Hf marker layers showed atomic diffusion much greater than expected
 - 100's of nm vs. 1's of nm
 - Most likely occurred during elevated temperatures, post-reaction
- Will investigate rapidly quenched materials and unstable fronts

Acknowledgements

- Sandia National Laboratories is a multi-program laboratory managed and operated by Sandia Corporation, a wholly owned subsidiary of Lockheed Martin Corporation, for the U.S. Department of Energy's National Nuclear Security Administration under contract DE-AC04-94AL85000.
- Questions?